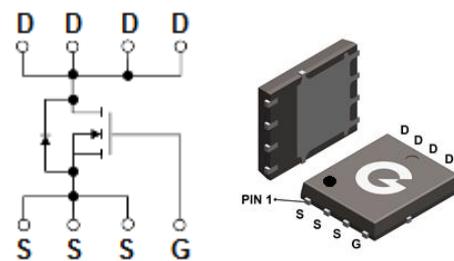


Features

- Super low $R_{DS(on)}$ and gate charge
- Advanced shielded-gate technology
- Green device available
- Excellent c_{dV}/d_t effect decline

HF

PDFN5x6-8L

Mechanical Data

- Case: PDFN5x6-8L
- Molding Compound: UL Flammability Classification Rating 94V-0
- Terminals: Matte tin-plated leads; solderability-per MIL-STD-202, Method 208

Ordering Information

Part Number	Package	Shipping Quantity	Marking Code
BL019N04TH-5DL8	PDFN5x6-8L	5000 pcs / Tape & Reel	019N04TH

Maximum Ratings (@ $T_A = 25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Value	Unit
Drain-to-Source Voltage	V_{DSS}	40	V
Gate-to-Source Voltage	V_{GSS}	± 20	V
Continuous Drain Current ($T_A = 25^\circ\text{C}$) *1	I_D	32	A
Continuous Drain Current ($T_A = 100^\circ\text{C}$) *1		22	A
Continuous Drain Current ($T_c = 25^\circ\text{C}$) silicon limited		168	A
Continuous Drain Current ($T_c = 100^\circ\text{C}$) package limited		100	A
Pulsed Drain Current ($t_p=10\mu\text{s}$)	I_{DM}	318	A
Single Pulse Avalanche Energy *3	E_{AS}	135	mJ

Thermal Characteristics

Parameter	Symbol	Value	Unit
Power Dissipation ($T_A = 25^\circ\text{C}$)	P_D	3	W
Thermal Resistance Junction-to-Case	$R_{\theta JC}$	1.5	K/W
Thermal Resistance Junction-to-Air *1	$R_{\theta JA}$	41	K/W
Operating Junction Temperature Range	T_J	-55 ~ +150	°C
Storage Temperature Range	T_{STG}	-55 ~ +150	°C

Electrical Characteristics (@ $T_A = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Test Condition	Min.	Typ.	Max.	Unit
Static Characteristics						
V_{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0\text{V}$, $I_D = 250\mu\text{A}$	40	-	-	V
$I_{DS(0)}$	Zero Gate Voltage Drain Current	$V_{DS} = 40\text{V}$, $V_{GS} = 0\text{V}$	-	-	1	μA
I_{GSS}	Gate-Body Leakage Current	$V_{GS} = \pm 20\text{V}$, $V_{DS} = 0\text{V}$	-	-	± 100	nA
On Characteristics						
$R_{DS(ON)}$	Static Drain-Source On-resistance * ²	$V_{GS} = 10\text{V}$, $I_D = 50\text{A}$	-	1.5	1.9	$\text{m}\Omega$
		$V_{GS} = 7\text{V}$, $I_D = 50\text{A}$	-	1.9	2.5	$\text{m}\Omega$
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS} = V_{GS}$, $I_D = 250\mu\text{A}$	2	3	4	V
Dynamic Characteristics						
C_{ISS}	Input Capacitance	$V_{GS} = 0\text{V}$ $V_{DS} = 25\text{V}$ $f = 1\text{MHz}$	-	5021	-	pF
C_{OSS}	Output Capacitance		-	1892	-	
C_{RSS}	Reverse Transfer Capacitance		-	177	-	
Switching Characteristics						
$t_{d(\text{ON})}$	Turn-on Delay Time	$V_{DD} = 20\text{V}$ $V_{GS} = 10\text{V}$ $R_G = 1.6\Omega$ $I_D = 85\text{A}$	-	13.5	-	ns
t_r	Turn-on Rise Time		-	7.2	-	
$t_{d(\text{OFF})}$	Turn-Off Delay Time		-	55	-	
t_f	Turn-Off Fall Time		-	8.6	-	
Q_G	Total Gate-Charge	$V_{DD} = 32\text{V}$ $V_{GS} = 10\text{V}$ $I_D = 100\text{A}$	-	79	-	nC
Q_{GS}	Gate to Source Charge		-	24	-	
Q_{GD}	Gate to Drain (Miller) Charge		-	22	-	
V_{plateau}	Gate Plateau Voltage		-	5	-	V
Source-Drain Diode Characteristics						
V_{SD}	Diode Forward Voltage * ²	$I_{SD} = 50\text{A}$, $V_{GS} = 0\text{V}$	-	0.82	1.2	V
t_{rr}	Reverse Recovery Time	$I_F = 40\text{A}$, $V_R = 30\text{V}$ $dI/dt = 100\text{A}/\mu\text{s}$	-	87	-	ns
Q_{rr}	Reverse Recovery Charge		-	135	-	nC

Notes:

1. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper
2. The data tested by pulsed , pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$
3. The E_{AS} data shows Max. rating. The test condition is $V_{DD} = 20\text{V}$, $V_{GS} = 10\text{V}$, $L = 0.5\text{mH}$
4. The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation

Ratings and Characteristics Curves (@ $T_A = 25^\circ\text{C}$ unless otherwise specified)

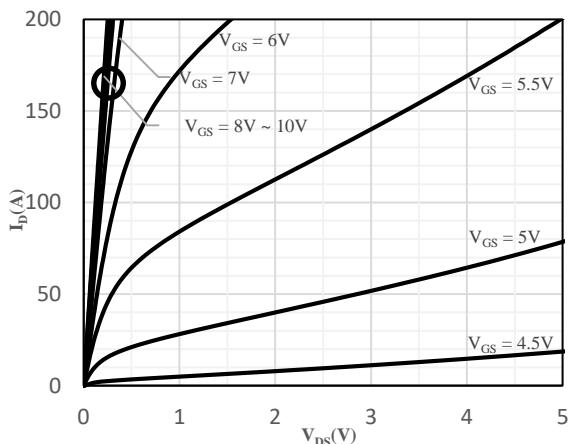


Fig 1 Output Characteristics

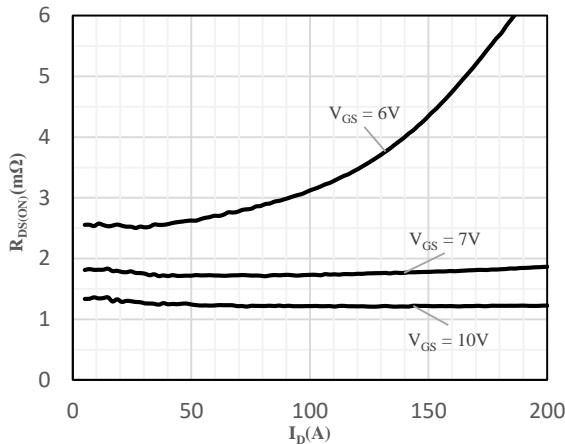


Fig 2 On-Resistance vs. Drain Current
and Gate Voltage

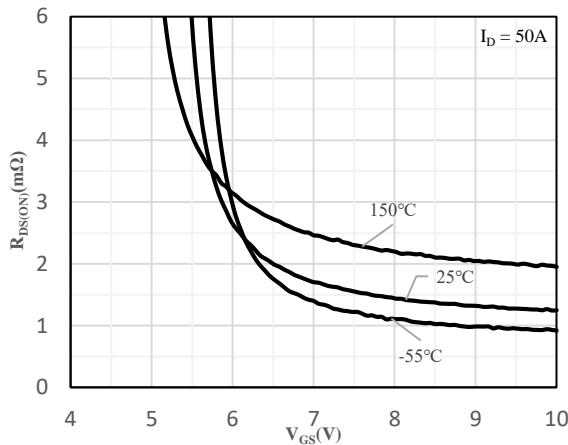


Fig 3 On-Resistance vs. Gate-Source Voltage

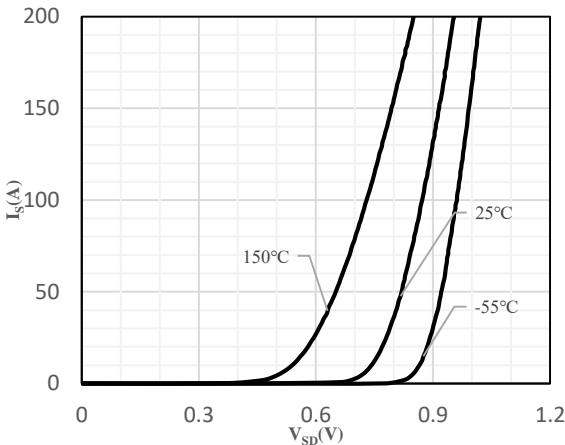


Fig 4 Body-Diode Characteristics

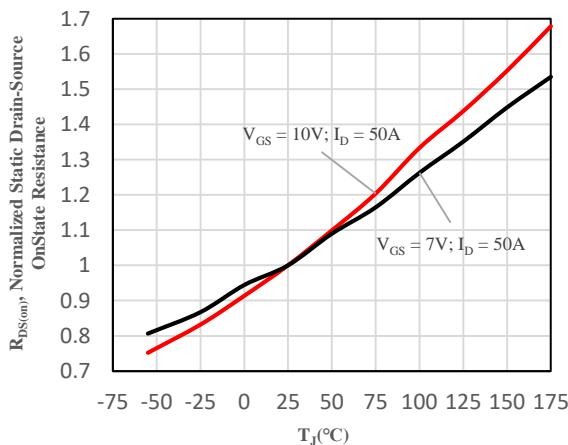


Fig 5 Normalized On-Resistance vs. Junction
Temperature

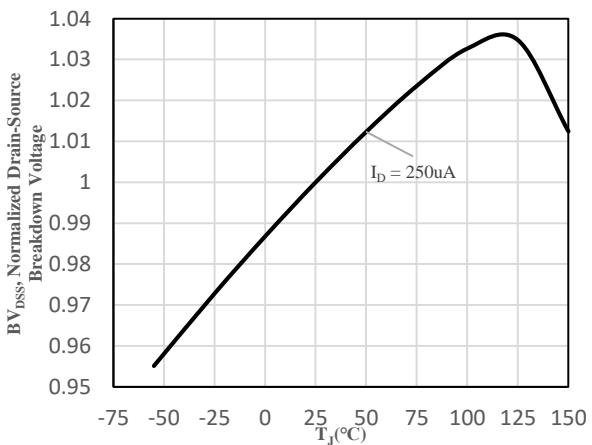


Fig 6 Normalized Drain-Source vs. Junction
Temperature

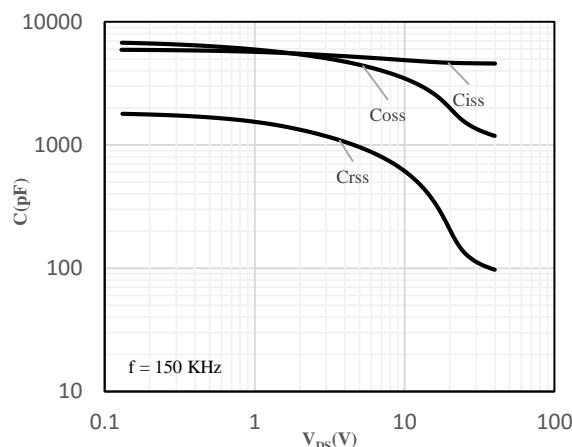


Fig 7 Capacitance Characteristics

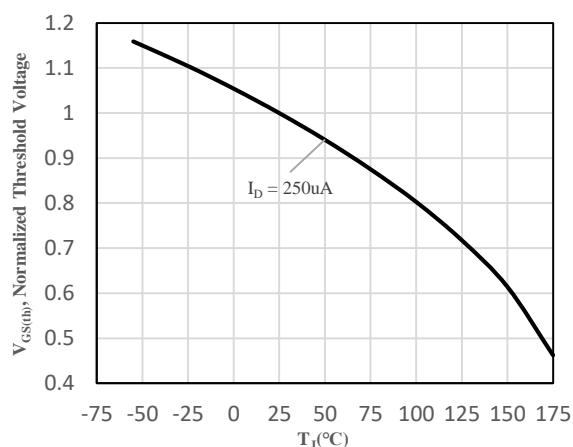


Fig 8 Normalized Gate Voltage vs. Junction Temperature

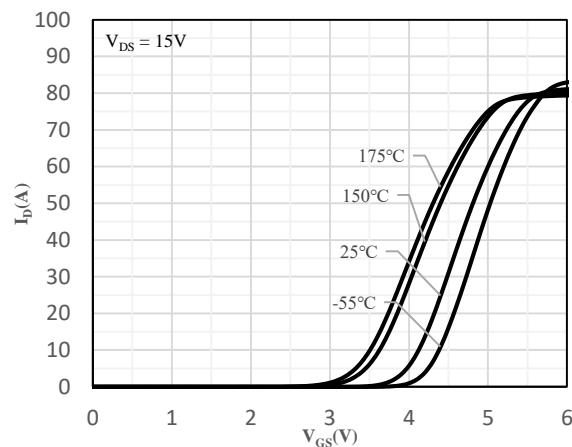


Fig 9 Transfer Characteristics

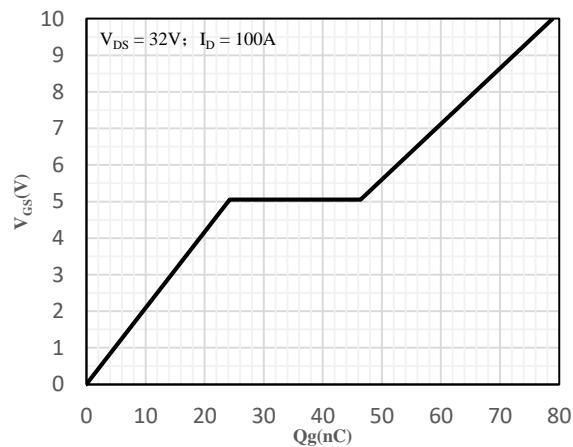


Fig 10 Gate-Charge Characteristics

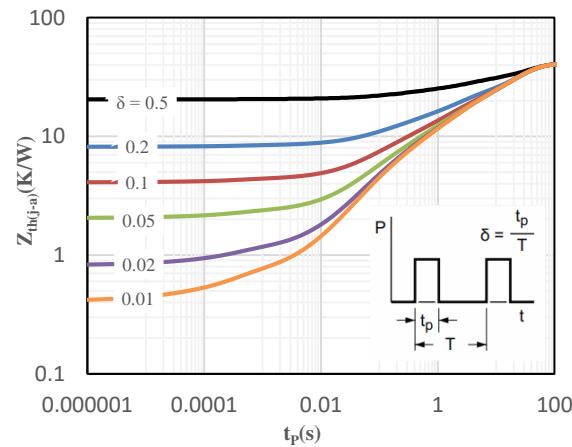


Fig 11 Maximum transient thermal impedance

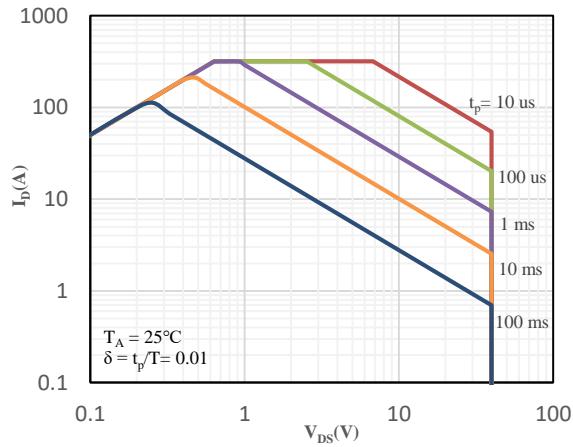
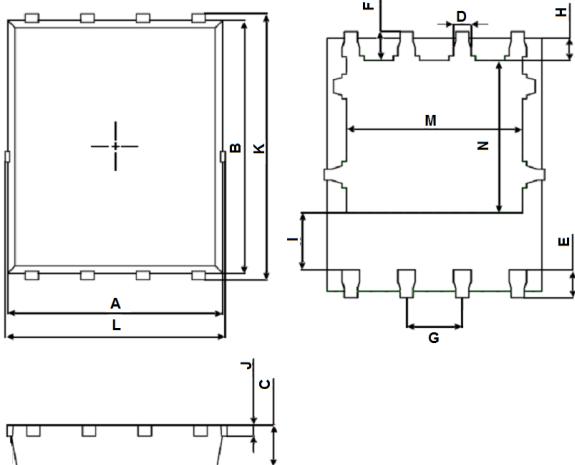


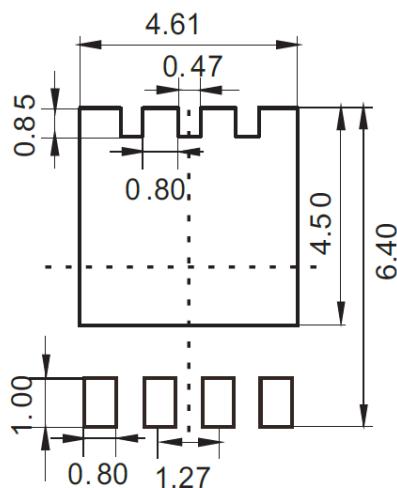
Fig 12 Safe Operation Area

Package Outline Dimensions (Unit: mm)



PDFN5x6-8L		
Dimension	Min.	Max.
A	4.824	4.976
B	5.674	5.826
C	0.900	1.000
D	0.350	0.450
E	0.559	0.711
F	0.574	0.726
G	1.250	1.290
H	0.424	0.576
I	1.190	1.390
J	0.154	0.354
K	5.974	6.126
L	4.944	5.096
M	3.910	4.110
N	3.375	3.575

Mounting Pad Layout (Unit: mm)

PDFN5x6-8L


IMPORTANT NOTICE

Changzhou Galaxy Century Microelectronics (GME) reserves the right to make changes without further notice to any product information (copyrighted) herein to make corrections, modifications, improvements, or other changes. GME does not assume any liability arising out of the application or use of any product described herein; neither does it convey any license under its patent rights, nor the rights of others.